

# Resource Summary Report

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## Zeiss Xradia 620 Versa X-ray microscope

RRID:SCR\_028320

Type: Tool

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### Proper Citation

Zeiss Xradia 620 Versa X-ray microscope (RRID:SCR\_028320)

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### Resource Information

**URL:** <https://pdf.directindustry.com/viewerCatalog/zeiss-metrologie-et-microscopie-industrielle/zeiss-xradia-versa-family/210459-1006465.html#open>

**Proper Citation:** Zeiss Xradia 620 Versa X-ray microscope (RRID:SCR\_028320)

**Description:** High-resolution 3D X-ray microscope (micro-CT) designed for non-destructive, submicron imaging of internal structures in materials science, electronics, and life sciences. It allows researchers to visualize 3D details at 500 nm resolution without cutting samples, using "Resolution at a Distance" (RaaD™) technology to image large or complex items.

**Synonyms:** ZEISS Xradia 620 Versa

**Resource Type:** instrument resource

**Keywords:** ABRF, 3D X-ray microscope, micro-CT, non-destructive, submicron, imaging, materials internal structures,

**Specification URL:** [https://raw.githubusercontent.com/SciCrunch/RRID-Instruments/refs/heads/main/PDF/SCR\\_028320.pdf](https://raw.githubusercontent.com/SciCrunch/RRID-Instruments/refs/heads/main/PDF/SCR_028320.pdf)

**Resource Name:** Zeiss Xradia 620 Versa X-ray microscope

**Resource ID:** SCR\_028320

**Alternate IDs:** Model\_Number\_ZEISS\_Xradia\_620\_Versa

**Alternate URLs:** <https://drexel.edu/core-facilities/facilities/material-characterization/our-instruments/xray-microscopy-tools>

**Record Creation Time:** 20260423T065300+0000

**Record Last Update:** 20260815T183319+0000

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### Ratings and Alerts

No rating or validation information has been found for Zeiss Xradia 620 Versa X-ray microscope.

No alerts have been found for Zeiss Xradia 620 Versa X-ray microscope.

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## Data and Source Information

**Source:** [SciCrunch Registry](#)

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## Usage and Citation Metrics

We have not found any literature mentions for this resource.